

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 06-077295

(43)Date of publication of application : 18.03.1994

(51)Int.Cl.

H01L 21/66

G01R 1/073

G01R 31/26

(21)Application number : 04-126971

(71)Applicant : NEC CORP

(22)Date of filing : 20.05.1992

(72)Inventor : SAKAGAMI NAOTO

(54) PROBE CARD

(57)Abstract:

PURPOSE: To obtain a good contact pressure, even if there is an error in parallelism in a probe card between a chip having a narrow pad and the probe card.

CONSTITUTION: A contactor 8 implanted upright on a flexible printed circuit board 10 is caused to be pressed to an electrode pad D of a chip 6 under test with an actuator 12 for which a pressure of solution is controlled by a pre-pressure pipe 13 through an input/output hole H and the pressure is detected and controlled with a pressure sensor provided within the actuator.

